



STORAGE DEVELOPER CONFERENCE

SNIA ■ SANTA CLARA, 2014

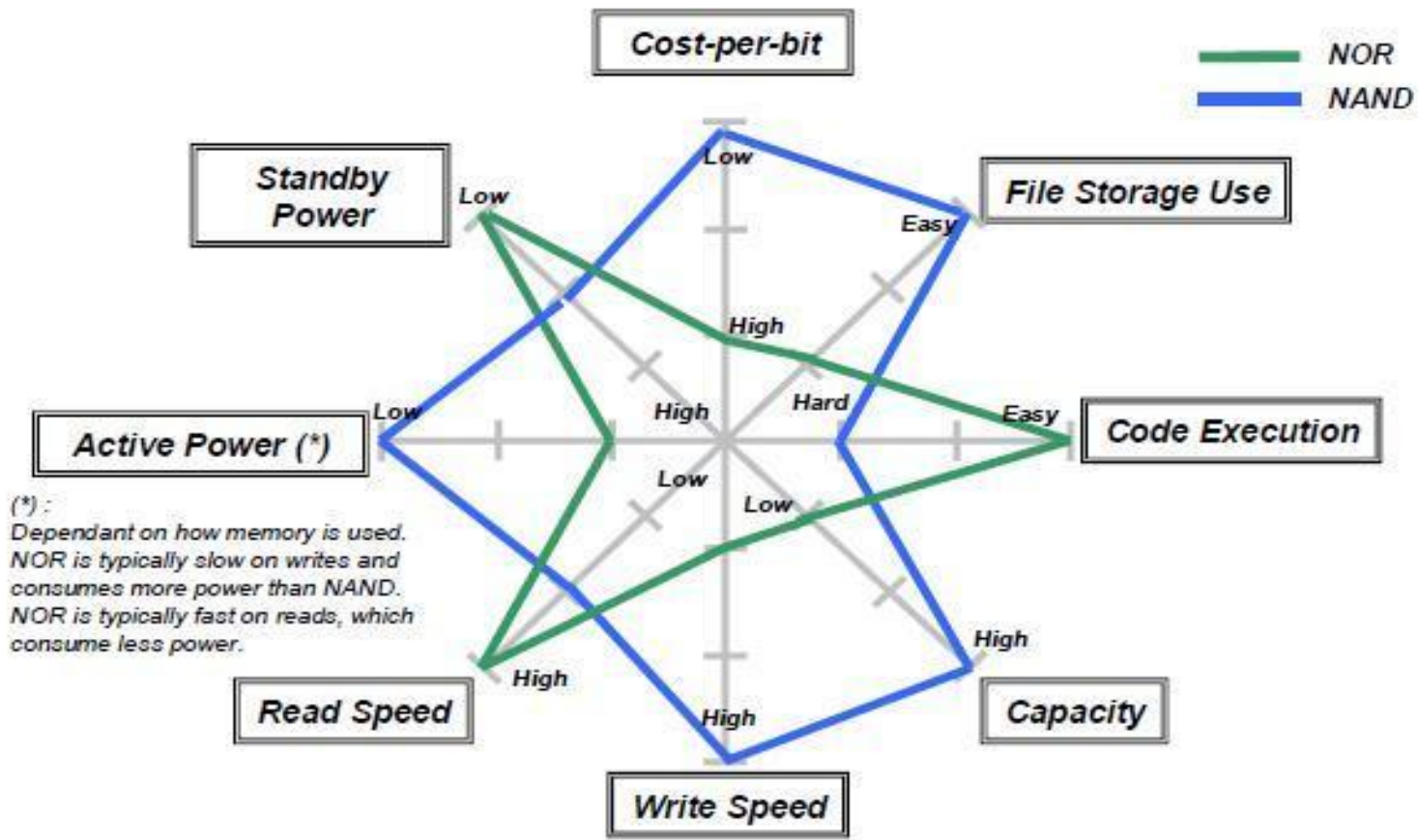
# Phase Change Memory and its positive influence on Flash Algorithms

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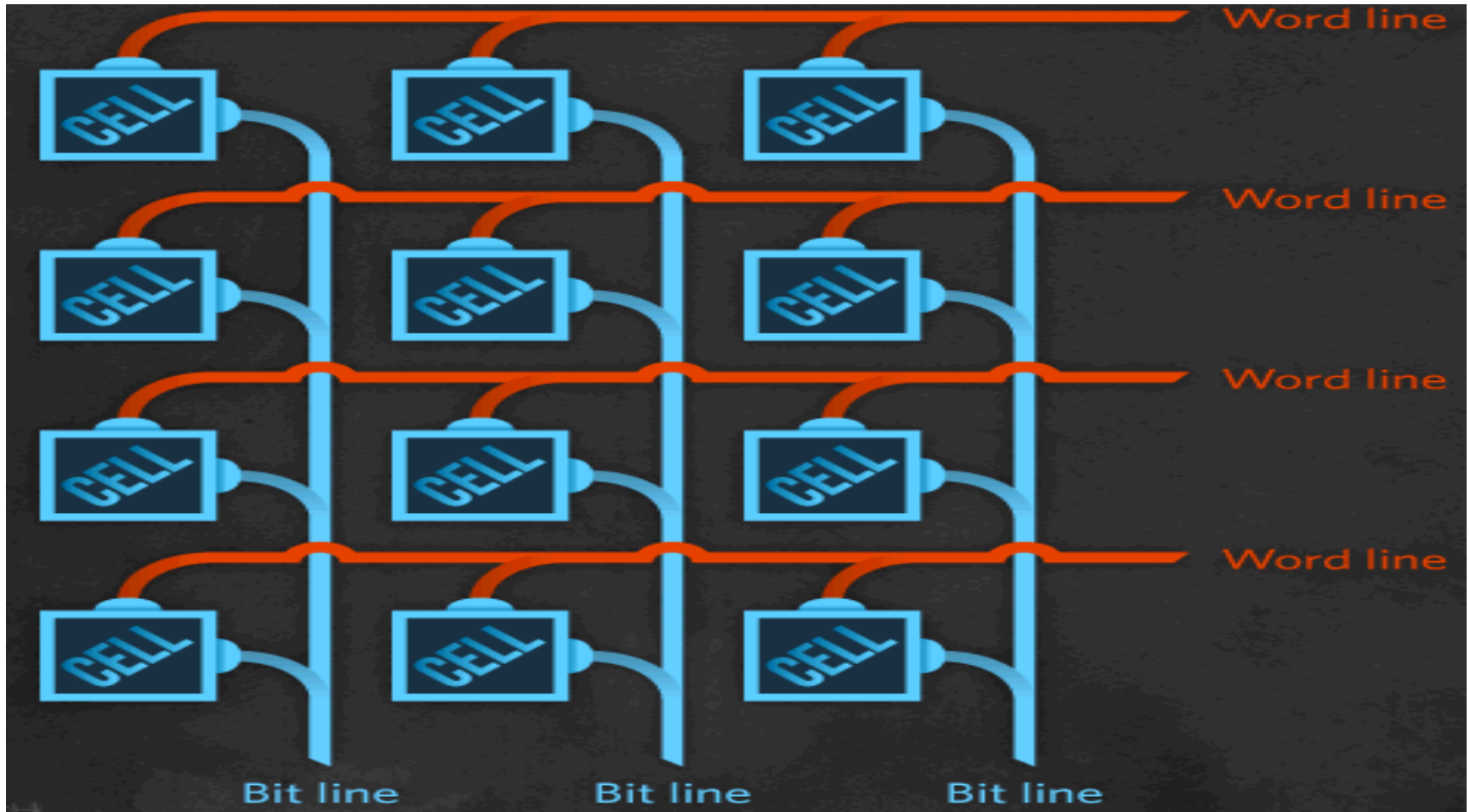
# Agenda

- ❑ Why NAND / NOR ?
- ❑ NAND and NOR Electronics
- ❑ Phase Change Memory (PCM) Architecture
- ❑ Determine the limitations of NAND based storage and transition plan to PCM
- ❑ Evaluate strategies: PCM attributes comparison
- ❑ Recognize the efficiency and benefits of PCM
- ❑ Futuristic : How can the industry leverage ?

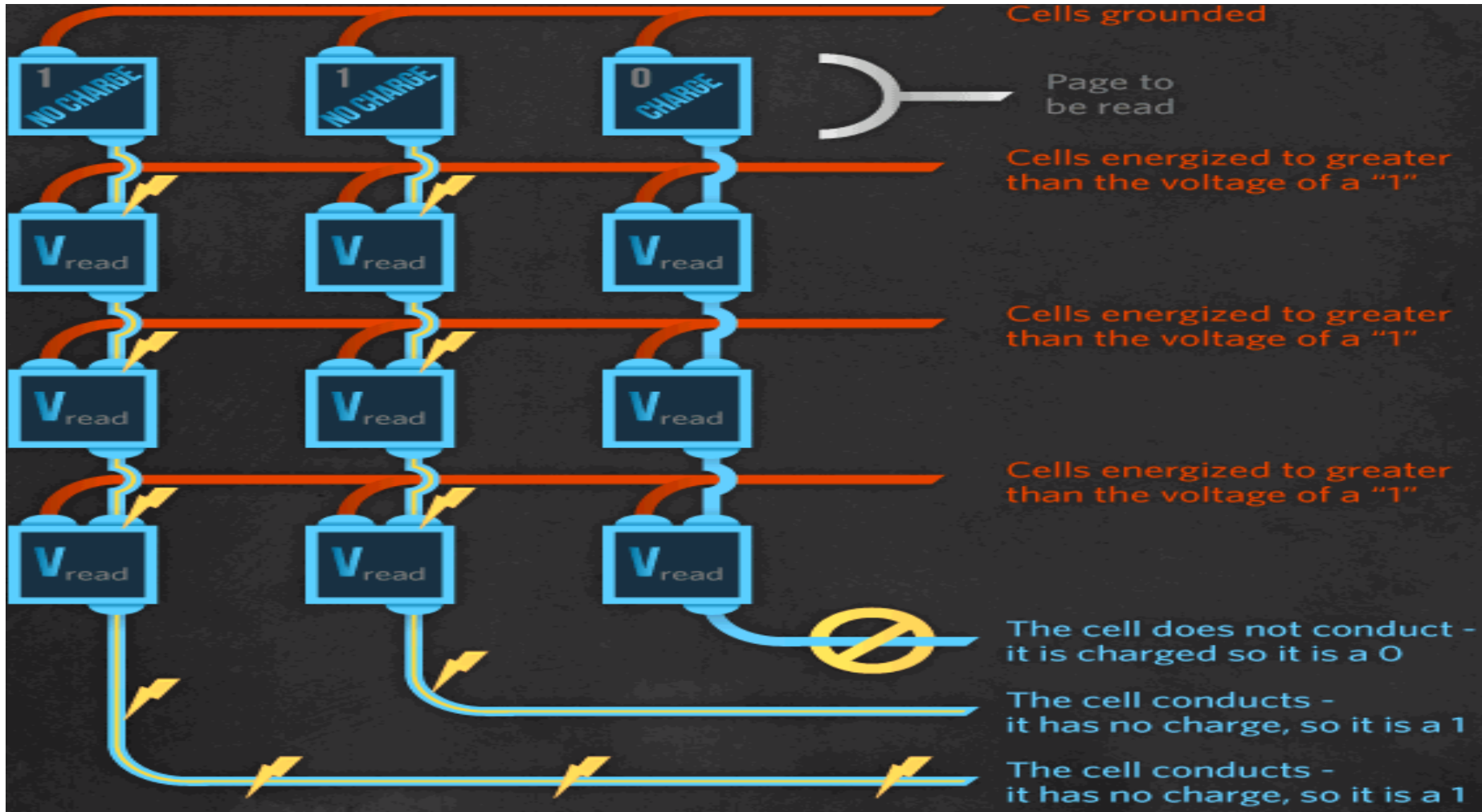
# Why NAND or NOR ?



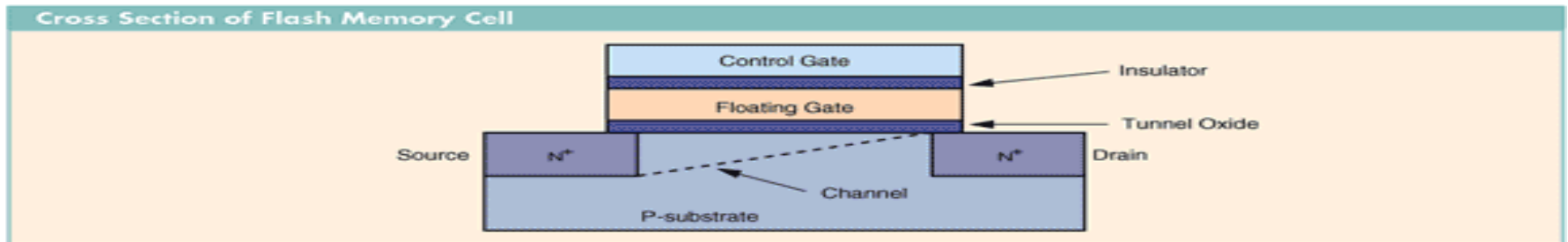
# NOR Electronics



# NAND Electronics



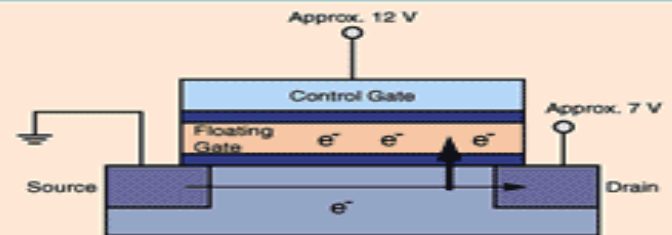
# Cross Section



## Principle of Operation (NOR type)

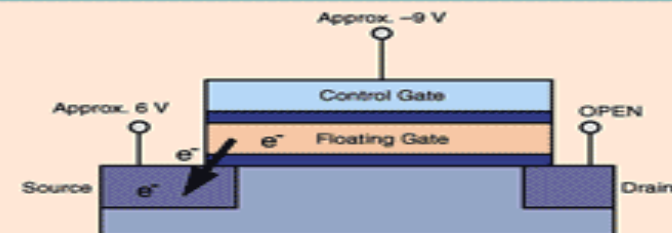
### Write

Applies the voltage at approx. 7 V to the drain to activate the electrons (hot electron) around the channel, then also applies at approx. 12 V to the control gate. In this way the electrons are injected into the floating gate through the tunnel oxide.



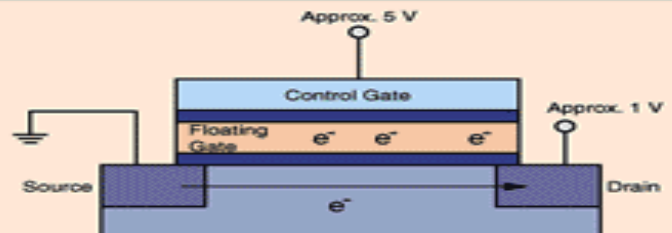
### Erase

Applies the voltage at approx. -9 V to the control gate and at approx. 6 V to the source. The electrons in the floating gate are pulled off and transferred to the source (tunnel current).



### Read

Applies the voltage at approx. 5 V to the control gate and at approx. 1 V to the drain. The state of the memory cell is distinguished by the current flowing between the drain and the source.



# How does Flash work ?

- ❑ Modulating charge stored within the gate of a MOS transistor.
- ❑ Presence of charge within the gate shifts the transistor's threshold voltage (1 or 0).
- ❑ Changing the bit's state requires removing the accumulated charge, which demands a relatively large voltage to suck the electrons off the floating gate.
- ❑ This burst of voltage is provided by a charge pump which takes some time to build up power.
- ❑ **Write time:** 0.1 millisecond for a block.

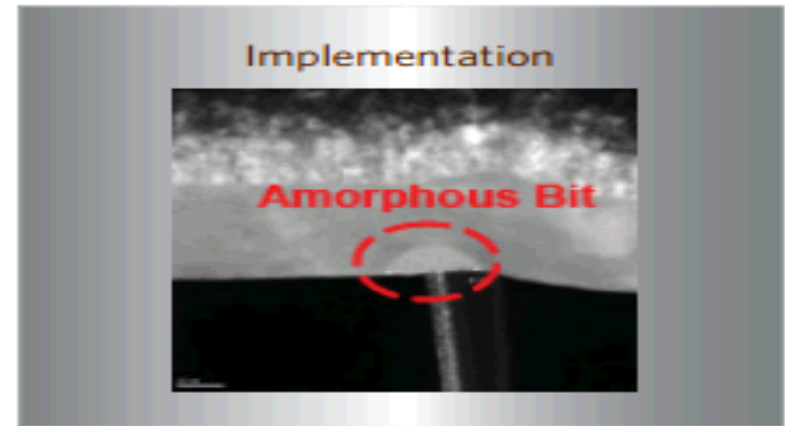
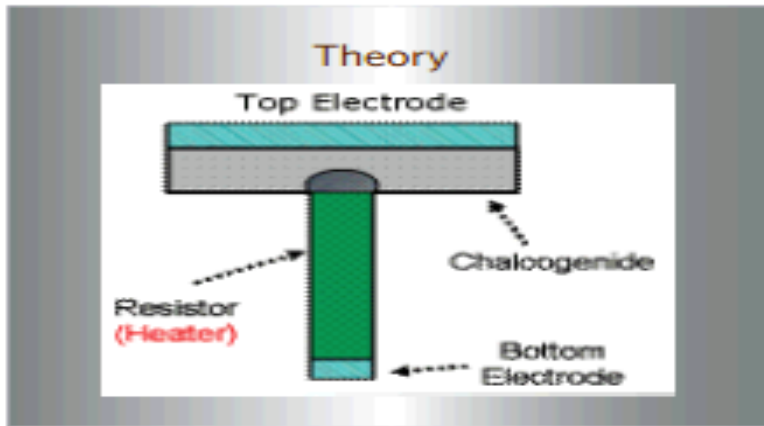
# Phase Change Memory (PCM) Architecture

- ❑ Chalcogenide glass ( Alloy of Germanium:Antimony:Tellurium 2:2:5 ).
- ❑ Material used in DVD-RW/CD-RW.
- ❑ Heat produced by passage of electric current changes states.
- ❑ **Two states:** Amorphous and Crystalline based on Electrical Resistivity.
- ❑ Amorphous represents binary 0 and is High Resistance state.
- ❑ Crystalline represents binary 1 and is Low Resistance state.
- ❑ Crystallization timescale : Order of 100 nanoseconds.
- ❑ **Partial Crystallization:** Two more states. **MLC PCM.**



# Phase Change Memory Architecture

Structure	Sample	Properties
Amorphous		<ul style="list-style-type: none"> <li>• Short-range atomic Order</li> <li>• High reflectivity</li> <li>• <b>High resistivity</b></li> </ul>
Polycrystalline		<ul style="list-style-type: none"> <li>• Long-range atomic Order</li> <li>• Low reflectivity</li> <li>• <b>Low resistivity</b></li> </ul>



Example phase change storage element

# Phase Change Memory : Industry Adoption

- ❑ Feb 2008 : Intel / STM revealed first MLC PRAM prototype.
- ❑ April 2010 : Numonyx announced the Omneo line of 128-Mbit NOR-compatible phase-change memories and Samsung announced shipment of its 512 Mb PCM in a multi-chip package (MCP) for use in mobile handsets by Fall 2010.
- ❑ June 2011 : IBM creates stable, reliable, multi-bit phase change memory with high performance and stability.
- ❑ July 2012 : Micron announced 45nm 1GB PCM chips.
- ❑ Aug 2014: HGST using PCM delivers three million random read I/Os (512-byte) and a random read access latency of 1.5 microseconds (i.e.) two orders of magnitude smaller than the fastest SLC NAND flash.

# Determine the limitations of NAND based storage and transition plan to PCM

- ❑ Scaling difficulties as chip lithography shrinks.
- ❑ Each burst of voltage across the cell causes degradation.
- ❑ Flash memory leaks charges which causes corruption and loss of data.
- ❑ Flash devices traps electrons to store information.  
Susceptible to data corruption from radiation ( unsuitable for space applications ).

# Determine the limitations of NAND based storage and transition plan to PCM (continued)

- ❑ The I/O interface of NAND flash does not provide a random-access external address bus. Rather, data must be read on a block-wise basis.
- ❑ Only finite amount of read/write cycles possible in a specific block.
- ❑ Repeated writes and rewrites of data blocks on a full SSD without giving the SSD time to perform garbage collection and cleaning can overwhelm the SSD controller's ability to manage free blocks and can lead to low observed performance.

# Determine the limitations of NAND : Write Amplification and Garbage Collection

Block X	A	B	C
	D	free	free
	free	free	free
	free	free	free

Block Y	free	free	free
	free	free	free
	free	free	free
	free	free	free

1. Four pages (A-D) are written to a block (X). Individual pages can be written at any time if they are currently free (erased).

Block X	A	B	C
	D	E	F
	G	H	A'
	B'	C'	D'

Block Y	free	free	free
	free	free	free
	free	free	free
	free	free	free

2. Four new pages (E-H) and four replacement pages (A'-D') are written to the block (X). The original A-D pages are now invalid (stale) data, but cannot be overwritten until the whole block is erased.

Block X	free	free	free
	free	free	free
	free	free	free
	free	free	free

Block Y	free	free	free
	free	E	F
	G	H	A'
	B'	C'	D'

3. In order to write to the pages with stale data (A-D) all good pages (E-H & A'-D') are read and written to a new block (Y) then the old block (X) is erased. This last step is *garbage collection*.

# Evaluate Strategies : PCM attributes comparison - 1

## Memory Characteristics PCM Offers Attributes of RAM & NAND



# Evaluate Strategies : PCM attributes comparison - 2

## Performance & Density Comparisons Circa 2011, 45nm Silicon

Attributes	DRAM	PCM	NAND	HDD
Non-Volatile	No	Yes	Yes	Yes
Idle Power	~100mW/GB	~1 mW/GB	~1 mW/GB	~10W
Erase / Page Size	No / 64Byte	No / 32Byte	Yes / 256KB	No / 512Byte
Write Bandwidth	~GB/s per die	50-100 MB/s per die	5-40 MB/s per die	~200MB/s per drive
Page Write Latency	20-50 ns	~1 us	~500 us	~5 ms
Page Read Latency	20-50 ns	~70 ns	~25 $\mu$ s	~5 ms
Endurance	∞	$10^8 \rightarrow 10^7$	$10^5 \rightarrow 10^4$	∞
Maximum Density	4Gbit	4Gbit	64Gbit	2TByte

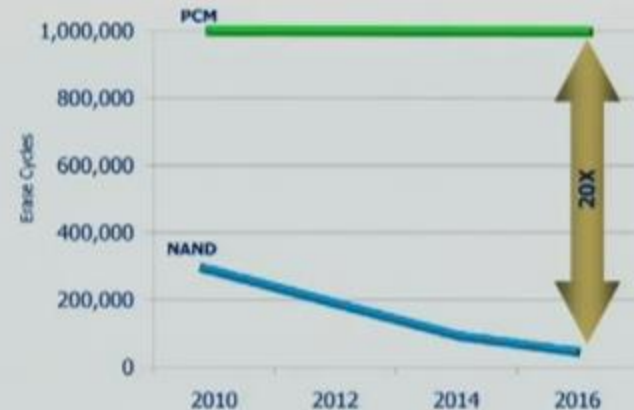
# Evaluate Strategies : PCM attributes comparison - 3

## Theoretical Chip Cost Factors

Silicon Cost Component		SLC PCM	DRAM	SLC NAND
Die Size	Cell Size (F <sup>2</sup> )	5.5	6.0	5.0
	4G Prod Example	1.0x	1.2x	1.0x
Wafer Complexity	Total Process Mask Count	-35	-34	30
	300mm cost structure	1.2x	1.2x	1.0x
Theoretical Die Cost Summary		1.2x	1.4x	1.0x

- PCM will be cheaper than DRAM at lithography parity
- PCM scales to lower densities better than NAND
- PCM attributes can also save cost at system level

## Endurance Scalability





# Evaluate Strategies : PCM attributes comparison - 4

Bit Alterability  
Ridiculously Simple

**NAND**

1. Read 4KB from NAND w/ECC
2. Write to RAM
3. Modify RAM
4. Locate new NAND page
5. Write new NAND page
6. Calculate & Write ECC
7. Mark old NAND page "dirty"
8. Eventually erase NAND block

**PCM**

1. Write 1 bit in PCM

Much less bus traffic  
"Hidden" Power  
Ridiculously Simple

# Recognize the efficiency and benefits of PCM over Flash (NAND/NOR)

- ❑ Memory element can be switched more quickly.
- ❑ Single bit can be changed (1 or 0) without needing to first erase an entire block of cells.
- ❑ PCM can endure 100 million write cycles.
- ❑ At normal working temperature of 85 degree C, it can retain data for 300 years.
- ❑ PCM exhibits higher resistance to radiation.
- ❑ PCM is ideal for workloads with “read often, write rarely” characteristics.

# Recognize the efficiency and benefits of PCM over Flash (NAND/NOR) (continued)

Attributes	PCM	DRAM	NAND	NOR	EEPROM
Bit Alterable	Green	Green	Red	Red	Green
Non-volatile	Green	Red	Green	Green	Green
Read Speed	Yellow	Green	Red	Yellow	Yellow
Write Speed	Yellow	Green	Yellow	Yellow	Red
Scaling	Green	Yellow	Yellow	Yellow	Red

PCM Attributes: This new class of non-volatile memory brings together the best attributes of NOR, NAND and RAM.

# Phase Change Memory : Limitations

- ❑ Degradation due to GST thermal expansion.
- ❑ Metal migration.
- ❑ Soldering creates high temperature which wipes pre-programmed PCM content.
- ❑ Need a way to program in PCM post soldering.
- ❑ Other unknown reasons.

# Quartz : September 2012

- ❑ Hitachi creates a prototype where High-precision laser is used to embed dots of binary code across a tiny piece of quartz glass.
- ❑ Optical Microscope paired with computer to decipher original data.
- ❑ Stress test: 2cm<sup>2</sup> of quartz heated to 1000 degree centigrade for 2 hours and still the data was recovered.
- ❑ Data density: Multi-layered quartz glass maxing out around 40MB per square inch.

# Futuristic : How can the Industry leverage?

- ❑ Leverage XIP (Execute in Place) feature of NOR for executables during bootup.
- ❑ If PCM gets widely deployed, exploit the bit alterability feature.
- ❑ Algorithms
  - ❑ The Flash write amplification and garbage collection algorithms will not be required anymore.
- ❑ Leverage “Flexible Storage Sharing” and “SmartIO” capability of Symantec Storage Foundation and High Availability on PCM.
- ❑ Measure the Evolution of MRAM, RRAM technologies in comparison with PCM.

# Q & A

□ Any questions / suggestions ?

**Thanks to SNIA SDC Team** 😊

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